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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
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Susumu Takahashi

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EXAMINER

SINGH, RACHNA

ART UNIT

PAPER NUMBER

2176

DATE MAILED: 10/24/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No. 09/775,646	Applicant(s) TAKAHASHI ET AL.	
	Examiner Rachna Singh	Art Unit 2176	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 17 August 2006.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 65-91 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 65-91 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | Paper No(s)/Mail Date. _____ |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

1. This action is responsive to communications: A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 08/17/06 has been entered.

2. Claims 65-91 are pending. Claims 33-64 have been cancelled. Claims 65, 73, 80, and 87 are independent claims.

Claim Rejections - 35 USC § 103

3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

4. Claims 65-66, 73-74, 80-81, and 87 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tamaki et al., US 2001/0014836 A1, 8/16/01 (filed 2/12/01, continuation filed 6/19/98).

Regarding Independent Claims 65, 73, 80, and 87, Tamaki discloses a production planning system in which a production plan comprises a data storage unit for storing parts list information providing a list of required parts, a parts stock storage section indicating parts stock information which meets the preamble, **a system for creating and/or editing structured parts**. See abstract and page 6, paragraphs [0117]-[0118]. Tamaki discloses a unit for storing production plan information on how to produce a particular product along with a parts list storage section for storing the parts list information providing a list of required parts which meets the limitation, **an assembly information storage configured to store assembly information including name of an assembly including a plurality of parts, and a plurality of parts information including name of parts utilized in said assembly**. See page 3, paragraph [0033], page 6, paragraph [0118], page 7, paragraph [0127]-[0128] and figures 1 and 3.

Examiner Note: A "product" is being interpreted as an "assembly". Furthermore, Examiner is interpreting "a list of parts information" as including the name of the parts used in the product.

Tamaki discloses a parts list storage section for storing the parts list information providing a list of required parts for a product which meets the limitation, **a parts information storage configured to store a plurality of said parts information, and parts attribute information including functions of parts corresponding to said parts information**. See page 6, paragraph [0118].

Tamaki discloses retrieving parts information from the production planning information and the parts list information stored in the data storage unit for use in a

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material resource planning unit which meets the limitation, **a parts information retrieving device configured to retrieve a plurality of parts information from said assembly information storage based on input assembly information, to retrieve the parts attribute information from said parts information storage based on the retrieved parts information, and to retrieve other parts information from said parts information storage based on the retrieved parts attribute information.**

Tamaki discloses an adjusting means in which superfluous or deficient parts are identified from the parts stock information and parts information. Superfluous parts are eliminated as are deficient parts and the production planning system is adjusted accordingly. See page 6, paragraph [0117]-[0122] and page 18. The parts list information is generated by the material resource plan unit for calculating the required amount of material resources based on this list. The production system receives production planning information including parts list information from the parts acquisition system. See page 6. The updated structural parts list is provided to the production planning system where it is stored in a data storage unit which meets the limitation, **an assembly information update device configured to replace the parts information corresponding to the assembly information with other parts information retrieved from the parts information storage, and to store the replaced parts information corresponding to the assembly information in a memory.** See page 18, second column.

Tamaki does not expressly state the "parts attribute information including functions of parts"; however, it would have been obvious to a person of ordinary skill in

the art at the time of the invention that a list of "required parts" would include the function of such parts because a "required part" would be identified by its use or function in the product.

In reference to claims 66, 74, and 81, Tamaki teaches that the parts information in storage may include information regarding a name of the part, a feature such as quantity consumed, a cost evaluation module, etc. See figures 24-27.

5. Claims 67-72, 75-79, 82-86, and 88-91 are rejected under 35 U.S.C. 103(a) as being unpatentable over Tamaki et al., US 2001/0014836 A1, 8/16/01 (filed 2/12/01, continuation filed 6/19/98) in view of Tegethoff, US 5,539,652, 7/23/96.

In reference to claim 67, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the

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circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc. in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In reference to claim 68, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher

defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In reference to claim 69, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can

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evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In reference to claim 70, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list

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created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In reference to claim 71, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of

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components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In reference to claim 72, Tamaki does not teach a compatibility prediction information output device configured to survey on predetermined items (i.e. packaging density, arrangement, and operation verification) based on parts information list created by parts information list creating/editing device and to create and output decision information for compatibility prediction based on results from said survey.

Tegethoff, however, teaches a method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing test of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The method models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing

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behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

Claims 75-79 are rejected under the same rationale used in claims 67, 69, 70, 71, and 72 respectively above.

Claims 82-86 are rejected under the same rationale used in claims 67, 69, 70, 71, and 72 respectively above.

Claims 88-91 are rejected under the same rationale used in claims 67, 69, 70, and 71 respectively above.

Response to Arguments

6. Applicant's amendments and arguments filed on 08/17/06 have been fully considered. Applicant's amendments have been addressed in the claim rejections above.

Applicant argues on page 13 of the Remarks that Tamaki is not directed to a system for creating or editing structured parts list information. Applicant further argues on page 14 that Tamaki discloses a parts list storage section but does not disclose that the parts list storage section stores information of different assemblies including parts,

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and information of a name of the parts. Examiner disagrees. Examiner notes that the claim does not necessarily teach "different assemblies". Tamaki discloses a production planning system in which a production plan comprises a data storage unit for storing parts list information providing a list of required parts, a parts stock storage section indicating parts stock information which meets the preamble, ***a system for creating and/or editing structured parts***. See abstract and page 6, paragraphs [0117]-[0118]. Tamaki discloses a unit for storing production plan information on how to produce a particular product along with a parts list storage section for storing the parts list information providing a list of required parts which meets the limitation, ***an assembly information storage configured to store assembly information including name of an assembly including a plurality of parts, and a plurality of parts information including name of parts utilized in said assembly***. See page 3, paragraph [0033], page 6, paragraph [0118], page 7, paragraph [0127]-[0128] and figures 1 and 3.

Examiner notes that a "product" is being interpreted as an "assembly".

Furthermore, Examiner is interpreting "a list of parts information" as including the name of the parts used in the product. Tamaki further discloses a parts list storage section for storing the parts list information providing a list of required parts for a product.

On page 15, Applicant argues Tamaki does not disclose the parts attribute information includes functions of parts. While Tamaki does not expressly state the "parts attribute information including functions of parts", it would have been obvious to a person of ordinary skill in the art at the time of the invention that a list of "required parts"

would include the function of such parts because a "required part" would be identified by its use or function in the product.

Regarding Applicant's arguments directed to the motivation of combining Tegethoff and Tamaki, Examiner disagrees. As stated in the rejections above, it would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

Applicant argues there is no basis for the combination because Tegethoff's simulation of an electronic circuit design is irrelevant to the system of Tamaki. Examiner disagrees. It has been held that a prior art reference must either be in the field of applicant's endeavor or, if not, then be reasonably pertinent to the particular problem with which the applicant was concerned, in order to be relied upon as a basis for rejection of the claimed invention. See *In re Oetiker*, 977 F.2d 1443, 24 USPQ2d 1443 (Fed. Cir. 1992). In this case, Tegethoff is concerned method for manufacturing test simulation in electronic circuit design. Tegethoff teaches a test simulator that simulates a manufacturing text of boards and multichip modules from design concept to aid the designer in selecting trade-offs in design. The methods models fault probabilities for the circuit design based on the components. Tegethoff further discloses the Manufacturing Test Simulator (MTSIM) which is a concurrent

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engineering simulation tool for manufacturing test, that is, a tool to predict manufacturing test behavior while a product is still being designed. See column 6. MTSIM uses pareto analysis in which a user can evaluate simulation results to determine faults, test coverage, etc. Pareto analysis can be done at three levels of abstraction including individual components, groups of components with the same part number, and groups of components. All part numbers are assigned a category based on level of integration and functionality. See column 11. Furthermore, Tegethoff teaches that the technology of circuit board assembly is evolving to support density demands of many modern circuit designs. Multi-chip modules and twelve-mil pitch surface mount technology (SMT) are frequently used to improve circuit density. SMT chip packages with lead counts of over 1000 are not uncommon. New fabrication processes are used to enable higher circuit densities usually have higher defect rates than older low density fabrication technologies. Tegethoff teaches identifying defects in packaging densities. See columns 1-4.

It would have been obvious to a person of ordinary skill in the art at the time of the invention to incorporate Tegethoff's prediction concerning operation, simulation, etc in a system of Tamaki's structured parts list because early prediction of manufacturing behavior drives design changes which optimize the product's manufacturability and testability, thus improving product quality and reducing cost and utilizing a parts list would help facilitate this prediction. See column 6 of Tegethoff.

In view of comments above, the rejection is maintained.

Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Rachna Singh whose telephone number is 571-272-4099. The examiner can normally be reached on M-F (8:30AM-6:00PM). If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Heather Herndon can be reached on 571-272-4136.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



Rachna Singh
10/20/06